

INTERNATIONAL STANDARD

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Methods for product accelerated testing

Méthodes d'essais accélérés de produits



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Méthodes d'essais accélérés de produits

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METHODS FOR PRODUCT ACCELERATED TESTING

FOREWORD

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IEC 62506 has been prepared by IEC technical committee 56: Dependability. It is an International Standard.

This second edition cancels and replaces the first edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) references have been updated;
- b) symbols have been revised;
- c) errors in 5.7.2.3 and Annex B, mainly, have been corrected;
- d) calculation errors in the examples of Annex B and Annex F have been corrected.

The text of this International Standard is based on the following documents:

Draft	Report on voting
56/2000/FDIS	56/2016/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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INTRODUCTION

Many reliability or failure investigation test methods have been developed and most of them are currently in use. These methods are used to either determine product reliability or to identify potential product failure modes, and have been considered effective as demonstrations of reliability:

- fixed duration,
- sequential probability ratio,
- reliability growth tests,
- tests to failure, etc.

Such tests, although very useful, are usually lengthy, especially when the product reliability that has to be demonstrated is high. The reduction in time-to-market periods as well as competitive product cost, increase the need for efficient and effective accelerated testing. Hence, the tests are shortened through the application of increased stress levels or by increasing the speed of application of repetitive stresses, thus facilitating a quicker assessment and growth of product reliability through failure mode discovery and mitigation.

There are two distinctly different approaches to reliability activities:

- the first approach verifies, through analysis and testing, that there are no potential failure modes in the product that are likely to be activated during the expected life time of the product under the expected operating conditions and usage profile;
- the second approach estimates how many failures can be expected after a given time under the expected operating conditions and usage profile.

Accelerated testing is a method appropriate for both cases, but used quite differently. The first approach is associated with qualitative accelerated testing, where the goal is identification of potential faults that eventually can result in product field failures. The second approach is associated with quantitative accelerated testing where the product reliability may be estimated based on the results of accelerated simulation testing that can be related back to the use of the environment and usage profile.

Accelerated testing can be applied to multiple levels of items containing hardware and software. Different types of reliability tests, such as fixed duration, sequential test-to-failure, success test, reliability demonstration or reliability growth or improvement tests can be candidates for accelerated methods. This document provides guidance on selected, commonly used accelerated test types. This document should be used in conjunction with statistical test plan standards such as IEC 61123, IEC 61124, IEC 61649 and IEC 61710.

The relative merits of various methods and their individual or combined applicability in evaluating a given system or item, should be reviewed by the product design team (including reliability engineering) prior to selection of a specific test method or a combination of methods. For each method, consideration should also be given to the test time, results produced, credibility of the results, data required to perform meaningful analysis, life cycle cost impact, complexity of analysis and other identified factors.

In this document the term "item" is used as defined in IEC 60050-192 covering physical products as well as software. Services and people are however not covered by this document.

METHODS FOR PRODUCT ACCELERATED TESTING

1 Scope

This document provides guidance on the application of various accelerated test techniques for measurement or improvement of item reliability. Identification of potential failure modes that can be experienced in the use of an item and their mitigation is instrumental to ensure dependability of an item.

The object of the methods is to either identify potential design weakness or provide information on item reliability, or to achieve necessary reliability and availability improvement, all within a compressed or accelerated period of time. This document addresses accelerated testing of non-repairable and repairable systems. It can be used for probability ratio sequential tests, fixed duration tests and reliability improvement/growth tests, where the measure of reliability can differ from the standard probability of failure occurrence.

This document also extends to present accelerated testing or production screening methods that would identify weakness introduced into the item by manufacturing error, which can compromise item reliability. Services and people are however not covered by this document.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-192 – *International Electrotechnical Vocabulary (IEV) – Part 192: Dependability*, available at <http://www.electropedia.org>

IEC 60300-3-5, *Dependability management – Part 3-5: Application guide – Reliability test conditions and statistical test principles*

IEC 60605-2, *Equipment reliability testing – Part 2: Design of test cycles*

IEC 60721 (all parts), *Classification of environmental conditions*

IEC 61123:2009, *Reliability testing – Compliance test plans for success ratio*

IEC 61124:2023, *Reliability testing – Compliance tests for constant failure rate and constant failure intensity*

IEC 61649:2008, *Weibull analysis*

IEC 61709, *Electric components – Reliability – Reference conditions for failure rates and stress models for conversion*

IEC 61710, *Power law model – Goodness-of-fit tests and estimation methods*

IEC 62429, *Reliability growth – Stress testing for early failures in unique complex systems*